

<b>Notice of References Cited</b>	Application/Control No. 10/531,208	Applicant(s)/Patent Under Reexamination UEDA ET AL.	
	Examiner Sin J. Lee	Art Unit 1795	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 11-322656	11-1999	Japan	Nishikubo et al.	N/A
	O	WO 02/079131 A1	10-2002	Japan	Hanabata et al.	N/A
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Chemical Abstract 1999:744383 for JP 11-322656 (Nishikubo et al).
	V	DERWENT English abstract for JP 11-322656 (Nishikubo et al).
	W	Chemical Abstract 137:302225 for WO 02/079131 A1 (Hanabata et al).
	X	Chemical Abstract 1998:475830 (Sakamizu et al).

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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